F-59 Characterization of Gemstones by Multiple Excitation EDXRF

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Publication date:

2010

Permanent link:

<https://doi.org/10.3929/ethz-b-000422960>

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Originally published in:

Powder Diffraction 25(2), <https://doi.org/10.1154/1.3454999>

11:40 F-54 Development of Quantification Method Using Fundamental Parameter Method for EDXRF
S. Hara, N. Kawahara, T. Matsuo, M. Doi, *Rigaku Corporation, Osaka, Japan*

12:00 F-59 Characterization of Gemstones by Multiple Excitation EDXRF
M. Haller, *Fischer Technology, Windsor, CT*
V. Rößiger, *Helmut Fischer GmbH, Sindelfingen, Germany*
A. Peretti, *Gemresearch Swisslab AG, Lucerne, Switzerland*
D. Günther, *ETH Zürich, Switzerland*

THURSDAY PM

XRD & XRF

CULTURAL HERITAGE I (SUPPORTED BY BRUKER)

EVERGREEN A

Chairs: **M. Walton**, Getty Conservation Institute, Los Angeles, CA
K. Eremin, Harvard Art Museum, Cambridge, MA

2:00 F-19 Invited—Analysis of Meissen Ceramics from the Hoffmeister Collection by HH-XRF
A.J. Shortland, K. Domoney, *Cranfield University, Swindon, UK*
S. Kuhn, *Bonham's Auctioneers, London, UK*

2:30 C-8 Invited—Analyzing Stratigraphy with a Dual XRD/XRF Instrument
G. Chiari, *Getty Conservation Institute, Los Angeles, CA*

3:00 D-3 An Archaeologist's Dilemma
K.D. Rogers, S. Beckett, S. Kuhn, *Cranfield University, Swindon, Wiltshire, UK*
A. Chamberlain, *Sheffield University, Sheffield, UK*
J. Clement, *University of Melbourne, Melbourne, Australia*

3:20 Break

3:50 F-50 Invited—Incorporating the Concept of Secondary Targets in Handheld X-ray Fluorescence to Increase Sensitivity of Minor Elements
C. McGlinchey, *The Museum of Modern Art, NY, NY*
B. Kaiser, T. Howe, *Bruker Elemental, Kennewick, WA*

4:20 F-79 Characterization of Silver Gelatin Fiber Based Photographic Papers using X-ray Fluorescence Spectroscopy
A. Martins, C. McGlinchey, L.A. Daffner, *Museum of Modern Art, New York, NY*
P. Messier, *LLC, Boston, MA*
A. Chapman, *University of Delaware Program in Art Conservation, Winterthur, DE*

THURSDAY PM

XRD

RIETVELD ANALYSIS II

EVERGREEN C

Chairs: **J. Kaduk**, Poly Crystallography Inc., Naperville, IL
S.T. Misture, NYS College of Ceramics at Alfred University, Alfred, NY

2:00 D-74 Invited—High-Resolution Powder X-ray Diffraction Study of Complex Minerals
S.M. Antao, *University of Calgary, Calgary, Alberta, Canada*